

# Non-Contact Inline Sheet Resistance Measurement Solutions

## DATA SHEET - EddyCus<sup>®</sup> TF inline

### HIGHLIGHTS

- Contact-free & real-time
- Precise measurement of thickness and sheet resistance of thin films (Ohm/sq)
- Wall thickness monitoring of low and high conductive substrates
- High degree of variability and flexibility according to specific customer requirements:
  - In- and ex-vacuo versions
  - Single-lane and multi-lane solutions
  - Monitoring of deposition processes with up to 99 sensor pairs
- Up to 3.000 samples / second
- Easy to handle software

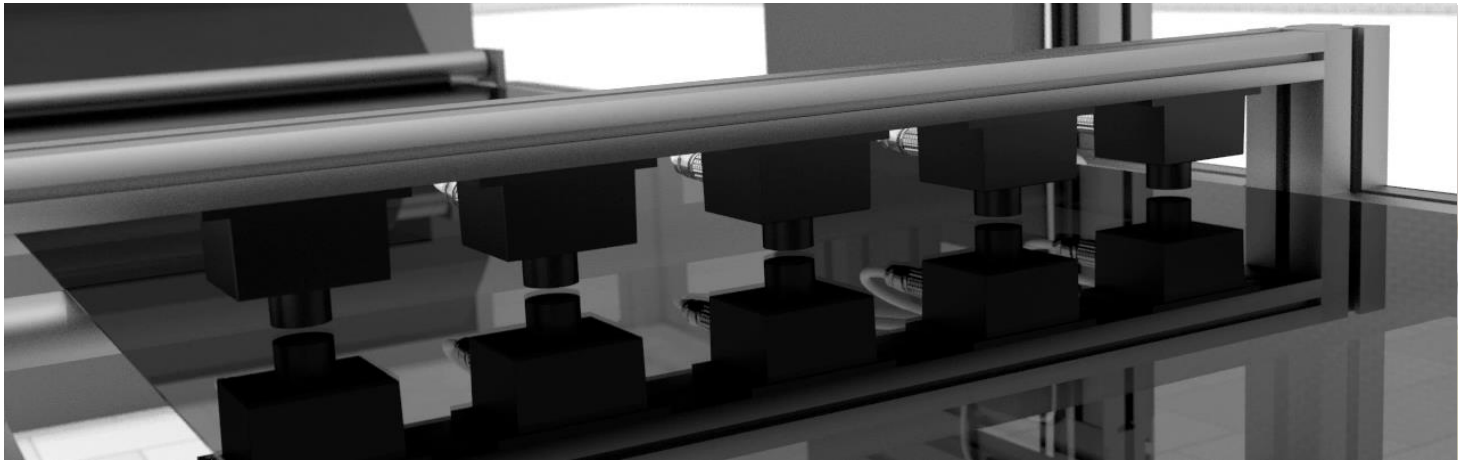
### APPLICATIONS

- > Architectural glass (LowE)
- > Touch screens & flat monitors
- > OLED & LED applications
- > smart-glass applications
- > Transparent antistatic foils
- > Photovoltaics
- > Semiconductors
- > De-icing & heating applications
- > Batteries & fuel cells
- > Packaging materials



# DATA SHEET

## EddyCus<sup>®</sup> TF inline – Inline Sheet Resistance Measurement



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Measurement gap size	1 / 5 / 10 / 15 / 25 / 50 mm (other on request)
Number of sensor pairs/monitoring lanes	1 – 99
Substrates	Glass/ PET-foils/ Wafer
Conductive layers	Metals/TCOs/CNTs/nanowires/graphene/grids/other
Sheet resistance range covered by every sensor	0.001 – 10 Ohm/sq < 2 % accuracy 10 – 100 Ohm/sq < 3 % accuracy 100 – 1.000 Ohm/sq < 5 % accuracy
Environment	Ex-vacuo/ in-vacuo < 60°C/ 140°F (on request < 90°C/ 194°F)
Sample rate	1 – 3,000 sample per second (higher on request)
Thickness	nm to mm in accordance with sheet resistance
Other integrated measurements	Substrate thickness and temperature / optical transmission
Other integrated available features	Hardware trigger / DMC or bar code reader

## SOFTWARE & HANDLING – EddyCus<sup>®</sup> TF inline Control

